

# UM74HCT612

## Memory Mapper

### Features

- Fully compatible with TTL, NMOS and CMOS devices.
- Expands 4 address lines to 12 address lines.
- Designed for paged memory mapping.
- High-current 3-state outputs.

### General Description

The UM74HCT612 essentially contains a 4-line to 16-line decoder and a 16-word by 12-bit RAM. It is designed to expand a microprocessor's memory address capability by 8 bits (from 4 to 12). That is, four bits of the memory address bus can be used to select one of 16 map registers that contain 12 bits each. These 12 bits are presented to the system memory address bus along with the unused memory address bit from the CPU. By periodically re-loading the mapper registers from the data bus, one can access any of the 16 pages of memory.

There are four modes of operation (read, write, map, and pass). When  $\overline{CS}$  (Chip Select) is active low, through D0 ~ D7, data may be read from or written into the map register selected by the register select inputs (RS0 ~ RS3) under

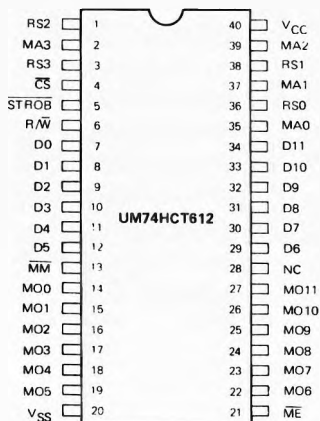
the control of R/W.

When  $\overline{CS}$  is high and  $\overline{MM}$  (Map Mode Control) is active low, the map operation will output the contents of map register selected by the map address input (MA0 ~ MA3).

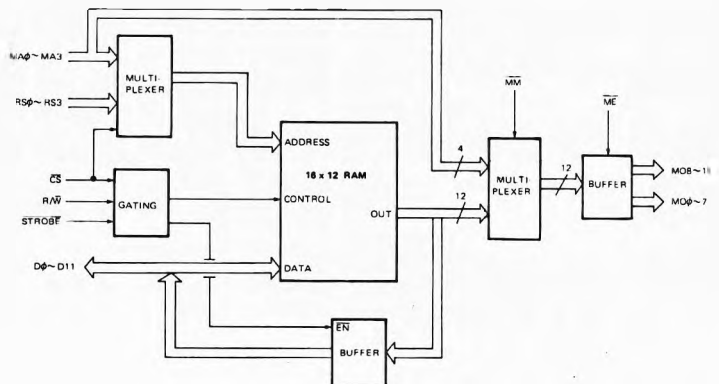
When  $\overline{CS}$  and  $\overline{MM}$  are both high (pass mode), the address bit on MA0 ~ MA3 appears at MO8 ~ MO11, respectively, with the other bits forcing low level. MO0 ~ MO7 are low.

All outputs are tri-state outputs with high current capability. The  $\overline{STROBE}$  input is used to enter data into selected map register during I/O operation. Map outputs are enabled by the  $\overline{ME}$  input.

### Pin Configuration



### Block Diagram



\*NC: Not connected.

**Absolute Maximum Ratings\***

D.C. Supply Voltage, $V_{DD}$ . . . . .	-0.5V to 7V (respect to $V_{SS}$ )
Input Voltage $V_I$ . . . . .	-0.5V to 7V
Operating Temperature . . . . .	0°C to 70°C
Storage Temperature . . . . .	-65°C to 150°C
Maximum Power Dissipation . . . . .	0.1W

**\*Comments**

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only. Functional operation of this device at these or any other conditions above those indicated in the operational sections of this specification is not implied and exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**D.C. Electrical Characteristics**

( $V_{DD} = 5V \pm 10\%$ ,  $T_A = 0^\circ\text{C} \sim 70^\circ\text{C}$ )

Symbol	Parameter	Min.	Typ.	Max.	Unit	Condition
$V_{DD}$	Power Supply	4.5	5	5.5	V	Recommended
$V_{IH}$	Input High-Level Voltage	2.0	-	-	V	Recommended
$V_{IL}$	Input Low-Level Voltage	-	-	0.8	V	Recommended
$V_{OHD}$	Output High-Level Voltage on D0 ~ D11	4.4	4.9	-	V	$I_{OH} = -20 \mu\text{A}$
		3.8	4.0	-	V	$I_{OH} = -6.0 \text{ mA}$
$V_{OHM}$	Output High-Level Voltage on M00 ~ M011	4.4	4.9	-	V	$I_{OH} = -20 \mu\text{A}$
		3.8	4.3	-	V	$I_{OH} = -8.0 \text{ mA}$
$V_{OLD}$	Output Low-Level Voltage on D0 ~ D11	-	0.001	0.1	V	$I_{OL} = 20 \mu\text{A}$
		-	0.3	0.4	V	$I_{OL} = 12 \text{ mA}$
$V_{OLM}$	Output Low-Level Voltage on M00 ~ M011	-	0.001	0.1	V	$I_{OL} = 20 \mu\text{A}$
		-	0.4	0.5	V	$I_{OL} = 20 \text{ mA}$
$I_{IN}$	Input Current	-1.0	-	1.0	$\mu\text{A}$	$V_{IN} = 5V \sim 0V$
$I_{OZ}$	OFF-State Output Current	-5	-	5	$\mu\text{A}$	$V_O = 3V \sim 0V$
$I_{CC}$	Steady Current	-	-	10	$\mu\text{A}$	$V_{IN} = V_{DD}$ or 0V, No Load.

**Timing Requirement and Switching Characteristics:** ( $V_{DD} = 5V \pm 10\%$ ,  $T_A = 0^\circ C$  to  $70^\circ C$ )

Parameter	Min.	Typ.	Max.	Unit	Condition
Pulse Width of $\overline{STROB}$ : $T_{sbw}$	75	–	–	ns	Recommended Value
$\overline{CS}$ Setup Time: $T_{cssu}$ ( $\overline{CS}$ low to $\overline{STROB}$ low)	20	–	–	ns	Recommended Value
R/ $\overline{W}$ Setup Time: $T_{rwsu}$ (R/ $\overline{W}$ low to $\overline{STROB}$ low)	20	–	–	ns	Recommended Value
RS Setup Time: $T_{rssu}$ (RS valid to $\overline{STROB}$ low)	20	–	–	ns	Recommended Value
DATA Setup Time: $T_{dasu}$ (D0–D11 valid to $\overline{STROB}$ high)	75	–	–	ns	Recommended Value
CS Hold Time: $T_{cshd}$ ( $\overline{STROB}$ high to $\overline{CS}$ high)	20	–	–	ns	Recommended Value
R/ $\overline{W}$ Hold Time: $T_{rwnd}$ ( $\overline{STROB}$ high to R/ $\overline{W}$ high)	20	–	–	ns	Recommended Value
RS Hold Time: $T_{rshd}$ ( $\overline{STROB}$ high to RS invalid)	20	–	–	ns	Recommended Value
DATA Hold Time: $T_{dahd}$ ( $\overline{STROB}$ high to D0 – D11 invalid)	20	–	–	ns	Recommended Value
RS to D0–D11: $TRSDV$ ( $T_{pHL}$ or $T_{pLH}$ )	–	39	75	ns	Figure 1 with $RL = 1K$ , $CL = 50P_f$  Timing Diagram see Figure 6.
$\overline{CS} \downarrow$ to D0–D11: $TCLDV$ ( $T_{pZL}$ or $T_{pZH}$ )	–	26	50	ns	
$\overline{CS} \uparrow$ to D0–D11, disable: $TCHDZ$ ( $T_{pHZ}$ or $T_{pLZ}$ )	–	38	65	ns	
R/ $\overline{W} \uparrow$ to D0–D11: $TWHDV$ ( $T_{pZL}$ or $T_{pZH}$ )	–	20	35	ns	
R/ $\overline{W} \downarrow$ to D0–D11, disable: $TWLDZ$ ( $T_{pHZ}$ or $T_{pLZ}$ )	–	30	50	ns	
$\overline{CS} \uparrow$ to M00–M011: $TCHQ$ ( $T_{pHL}$ or $T_{pLH}$ )	–	48	85	ns	Figure 1 with $RL = 1K$ ; $CL = 50P_f$  Timing Diagram see Figure 7.
$\overline{MM} \downarrow$ to M00–M011: $TMLQ$ ( $T_{pHL}$ or $T_{pLH}$ )	–	20	40	ns	
$\overline{MM} \uparrow$ to M00–M011: $TMHQ$ ( $T_{pHL}$ or $T_{pLH}$ )	–	22	40	ns	
MA to M00–M011, $\overline{MM} = \text{low}$ : $TAVQ1$ ( $T_{pHL}$ or $T_{pLH}$ )	–	39	70	ns	
MA to M08–M011, $\overline{MM} = \text{high}$ : $TAVQ2$ ( $T_{pHL}$ or $T_{pLH}$ )	–	13	30	ns	
$\overline{ME} \downarrow$ to M00–M011: $TELQ$ ( $T_{pZL}$ or $T_{pZH}$ )	–	17	30	ns	
$\overline{ME} \uparrow$ to M00–ME11, disable: $TEHQZ$ ( $T_{pHZ}$ or $T_{pLZ}$ )	–	14	25	ns	

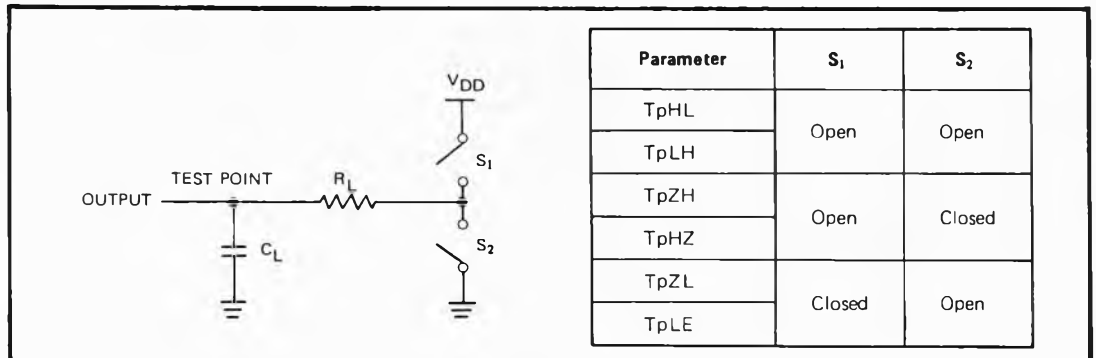
**Note:** See Figures 2, 3, 4, and 5, for definitions of  $T_{pLH}$ ,  $T_{pHL}$ ,  $T_{pHZ}$ ,  $T_{pLZ}$ ,  $T_{pZH}$ ,  $T_{pZL}$ .

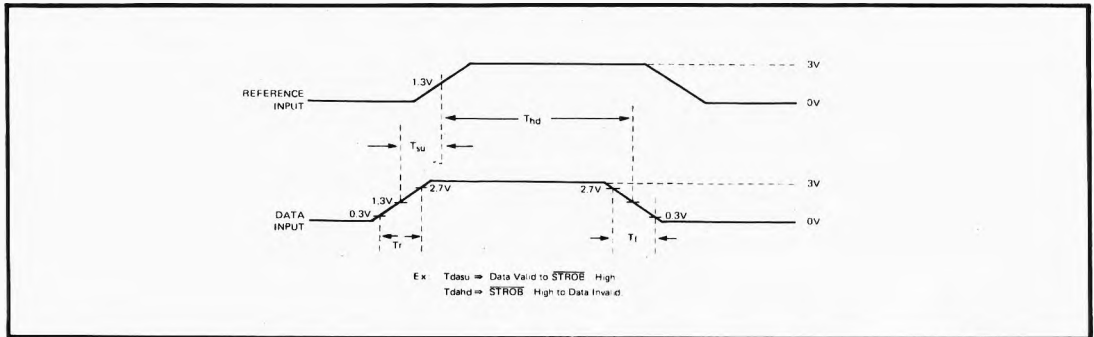
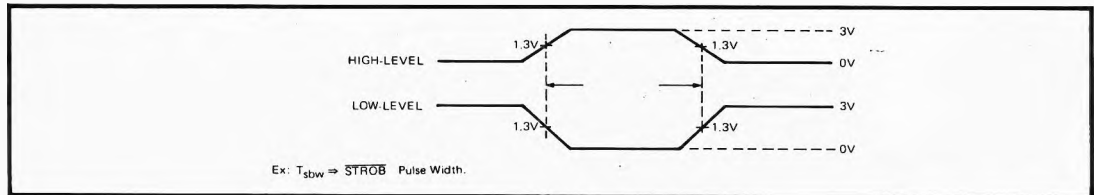
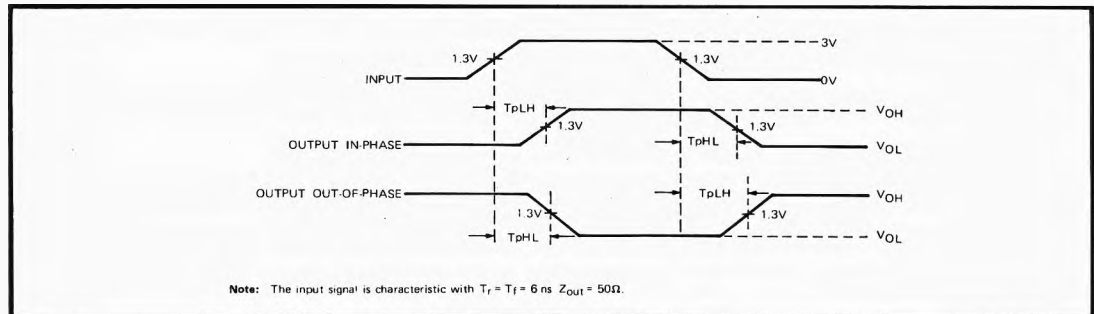
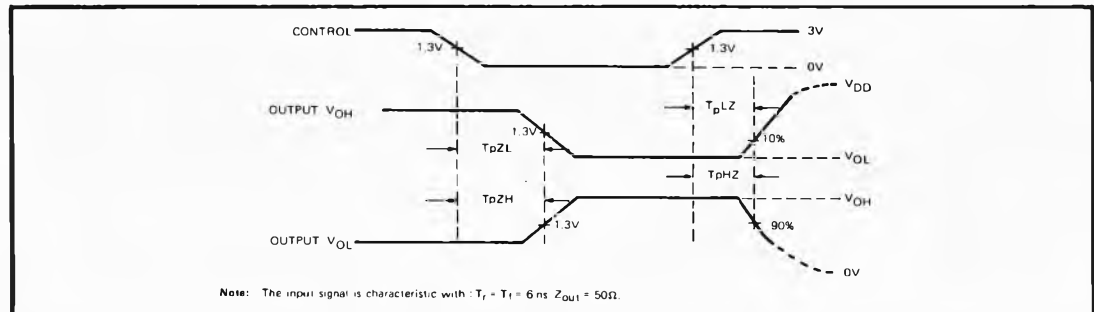
**Pin Description**

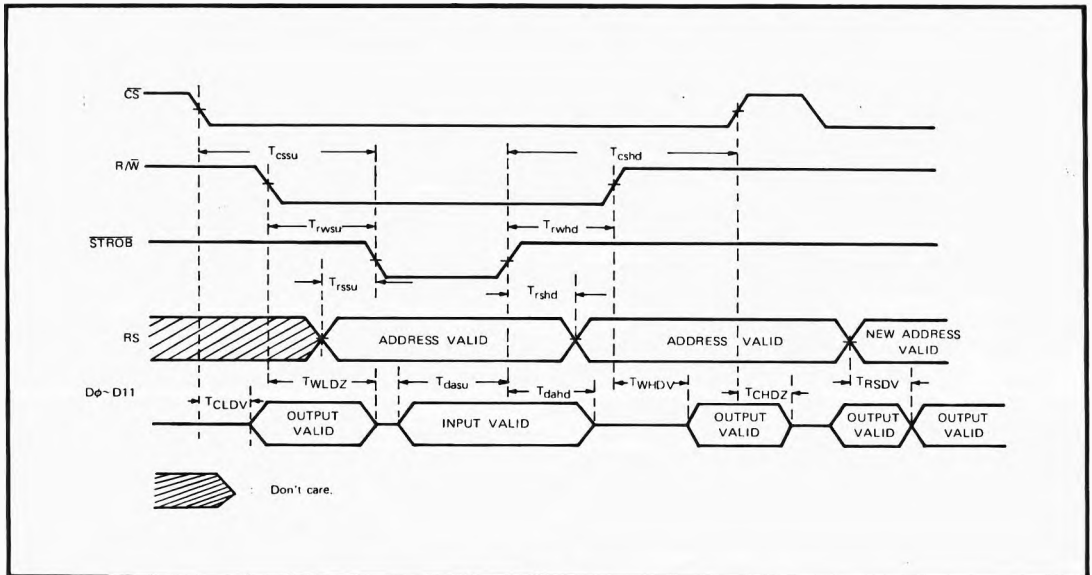
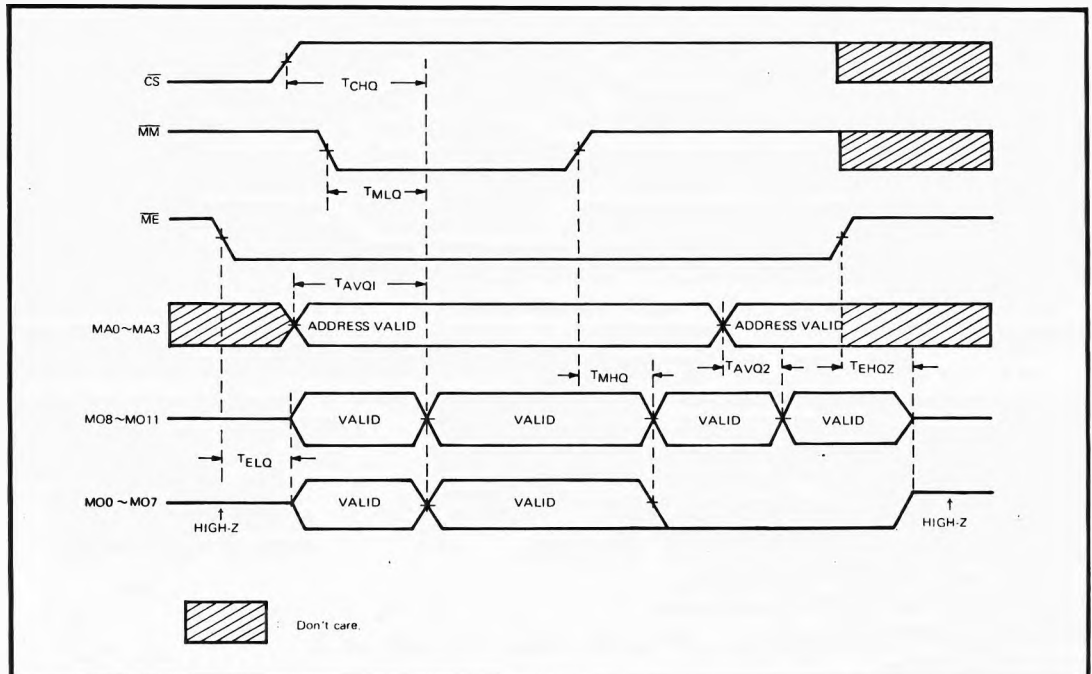
Symbol	Description
D0–D11	I/O connection to data and control bus. Used for reading from or writing into the map register.
RS0–RS3	Register select inputs for I/O operation.
R/W	Read or write control pin used in I/O operation. When low, data bus is used to write into register. When high, data bus is used to read from register.
STROB	Strobe input. Used to enter data into register.
$\overline{CS}$	Chip select input. When low, the Read and Write Modes are active.
MA0–MA3	Inputs to select one of 16 registers, when in map mode.
MO0–MO11	Map outputs. Present the map register contents to the system memory address bus in the map mode. When in pass mode, these outputs provide the map address data on MO8 – MO11 and low level on MO0–MO11.
$\overline{MM}$	Map mode input. When low, the map mode is active; when high, it is in pass mode.
$\overline{ME}$	Map output enable pin. When low, outputs MO0–MO11 are active. When high, these are high impedance.

**Function Table**

$\overline{CS}$	$\overline{MM}$	R/W	STROBE	Operation
0	X	0	0	Write Mode, D0 ~ D7 $\Rightarrow$ Selected Register.
0	X	1	X	Read Mode, Selected Register $\Rightarrow$ D0 ~ D7.
1	0	X	X	Map Mode, Register Contents $\Rightarrow$ MO0 ~ MO11 (If $\overline{ME} = 0$ ).
1	1	X	X	Pass Mode MA0 ~ MA3 $\Rightarrow$ MD8 ~ MD11 and MD0 ~ MD7 are all low (If $\overline{ME} = 0$ ).

**Parameter Measurements**
**3-State Output**

**Figure 1**

**Set-Up and Rise, Fall Times**

**Figure 2**
**Pulse Duration**

**Figure 3**
**Delay Times**

**Figure 4**
**Enable or Disable**

**Figure 5**

**Timing Waveforms**
**Read and Write Mode**

**Figure 6**
**Map and Pass Mode**

**Figure 7**